

CHIPIX65: Sviluppo di un pixel chip innovativo in tecnologia CMOS 65 nm per altissimi flussi di particelle e radiazione agli esperimenti di HL-LHC e futuri collider di nuova generazione

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on behalf of the CHIPIX65 project



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Scopo e partecipanti

Scopo: Lo sviluppo di un pixel chip innovativo in tecnologia CMOS 65nm (TSMC) resistente a altissimi flussi di particelle e radiazione si inserisce nella partecipazione italiana al progetto CERN RD53, di cui CHIPIX65 è parte.

Coordinatore: **N. Demaria (Torino)**

Unità partecipanti: **Bari, Bergamo + Pavia, Milano, Padova, Perugia, Pisa, Torino, Lecce (dal 2016)**

Persone:

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Attività in corso: IP blocks

BandGap: Pavia

ADC: Bari

DAC: Bari

SER/DES: Pisa

s-LVDS: Pavia, Pisa

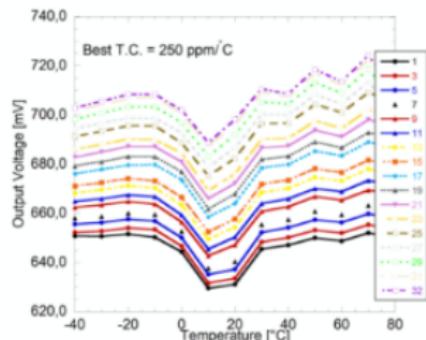
DICE SRAM: Milano

BLOCK	DIMENSIONS	POWER	Performance / Main-Characteristics
Band-Gap	$100 \times 270 \mu\text{m}^2$	$65 \mu\text{W}$	based on MOS only
10-bit DAC	$140 \times 240 \mu\text{m}^2$	$150 \mu\text{W}$	$\text{DNL} < 0.4 \text{ LSB}$, $\text{INL} < 1 \text{ LSB}$
12-bit ADC	$308 \times 535 \mu\text{m}^2$		1V, 16-ch, 5kSample/s
SER	$100 \times 56 \mu\text{m}^2$	2.3 mW	2 Gbps
DES	$180 \times 56 \mu\text{m}^2$	17.8 mW	2 Gbps
sLVDS-TX	$160 \times 160 \mu\text{m}^2$	2 mW	1.2 Gbps
sLVDS-RX	$70 \times 80 \mu\text{m}^2$	0.2 mW	1.2 Gbps
Dice S-RAM	$1.8 \times 3.3 \mu\text{m}^2$		SEE recover in 2.5ns

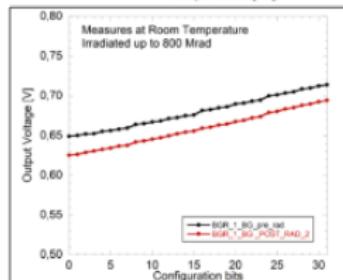
BandGap

Il BandGap è un blocco importante perché deve fornire un riferimento indipendente da T e dalle radiazioni

Pavia / Bg



- Temperature range: from -40°C to 80°C
 - Trimming resistor with 5 bits resolution
 - Power Supply: 1.2V
 - Power Consumption: 50 μW
- Irradiated up to 800 Mrad (Si) with protons at 10 MeV
- The reference output voltage has a limited shift under irradiation around 4 %



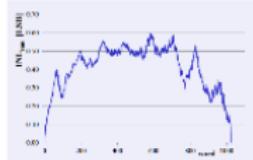
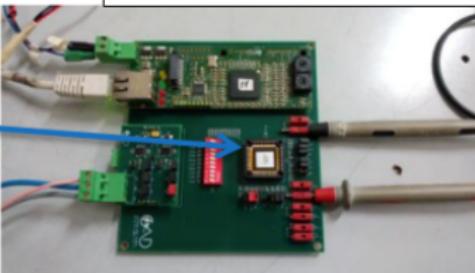
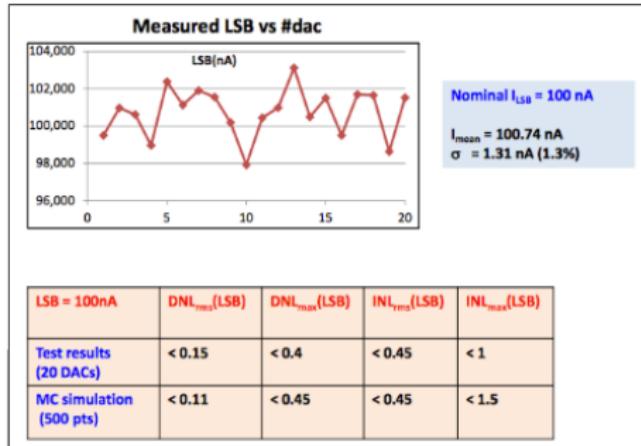
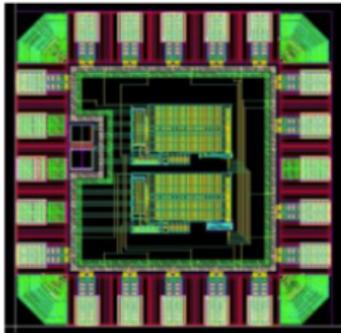
New version designed and submitted in May 2015, now starting test:

- mismatch variations < 2%, process ~4%
- trimming can correct process, radiation variations, leaving at max mism@2%

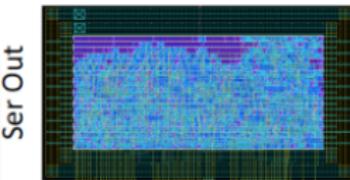
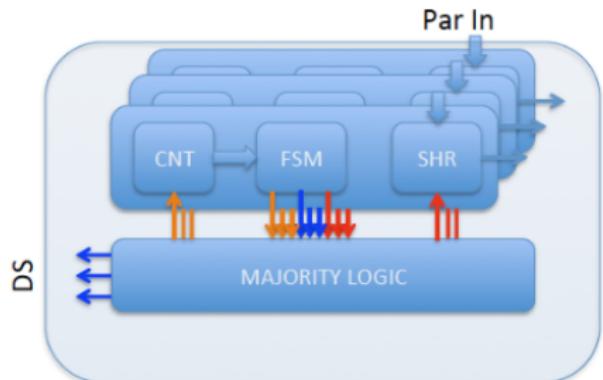
DAC

Bari

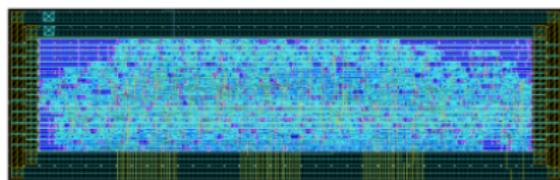
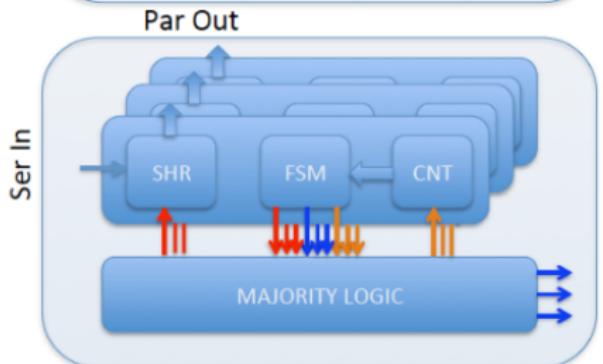
- Important for ASIC biasing
- 10-bit **current-steering** Digital-to-Analog converter; LSB = 100 nA (nominal)
 - Architecture: 8+2 segmented DAC (2 binary weighted + 8 unitary decoded cells)
- Characterised in Lab
- Now under radiation test at Padova x-ray machine



SER / DES



- 20 bits – 2Gbps
- Standard Cells + TMR
- FSM => Counter Reset, Load, Data Strobe (DS)
- H = 56um – W = 100um (299 cells)
- Power = 2.35 mW (max)

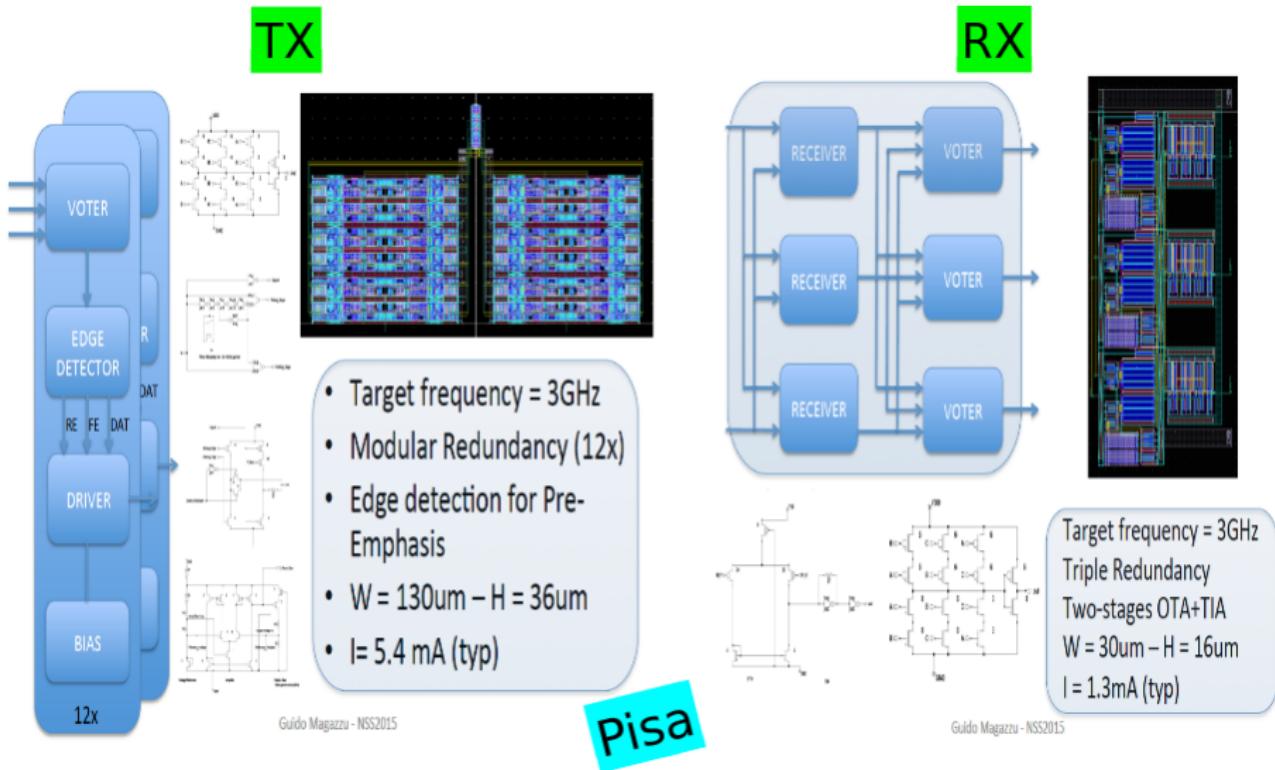


- 20 bits – 2Gbps
- Standard Cells + TMR
- FSM => Counter Reset, Data Valid (DV)
- H = 56um – W = 180um (556 cells)
- Power = 17.85mW (max)

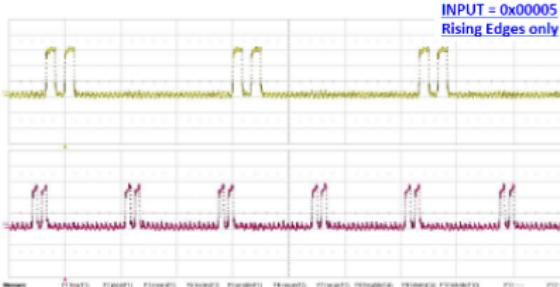
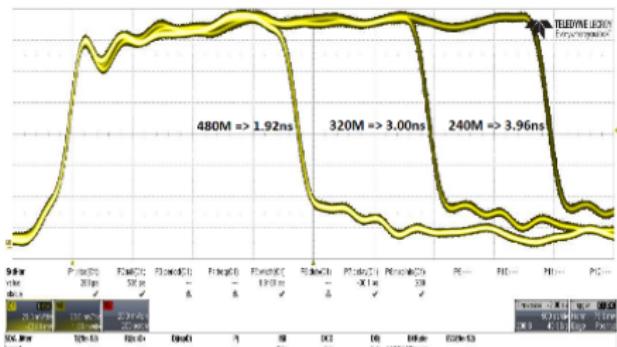
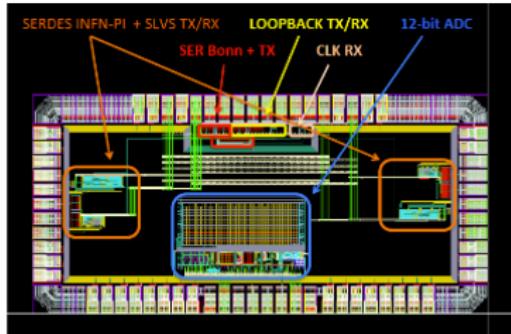
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Guido Magazzu - NSS2015

s-LVDS

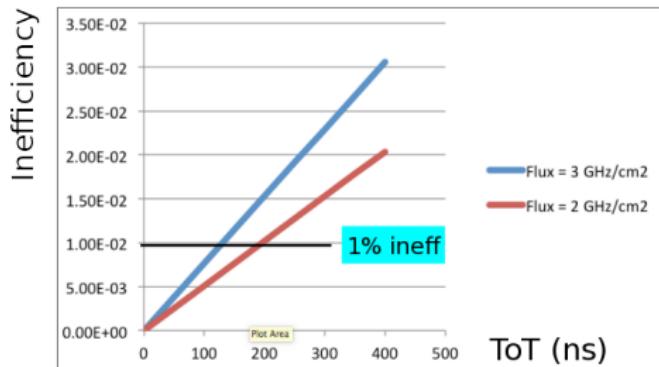


SER / DES v. 2



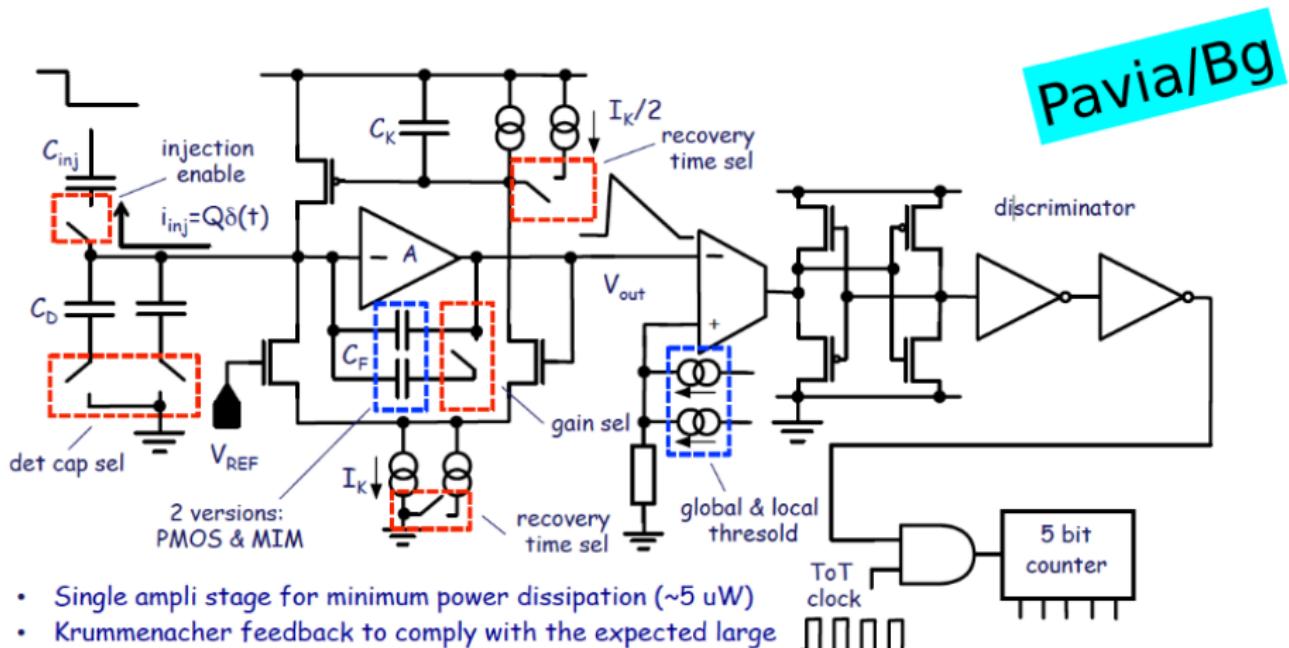
Requirements:

- Compact: $\approx 50\%$ of $(50 \times 50 \mu\text{m}^2)$; $25 \times 50 \mu\text{m}^2$ or $35 \times 35 \mu\text{m}^2$
- Low power: $< 4 \mu\text{A}$ (or $5 \mu\text{W}$)
- Low threshold: $< 1000 \text{ e}^-$
- Dead-time inefficiency $\ll 1\% @ 3 \text{ GHz/cm}$ (200 PU)
- Digitization: desired at least 4-bits

CONSEQUENCES

- 1.<ToT> should be $< 150\text{ns}$ (200PU)
- 2.<ToT> should be $< 200\text{ns}$ (140 PU)
3. For 4-bit (600e^-) ToT freq $> 100 \text{ MHz}$
4. For 5-bit (300e^-) ToT freq $> 200 \text{ MHz}$

Asynchronous AFE

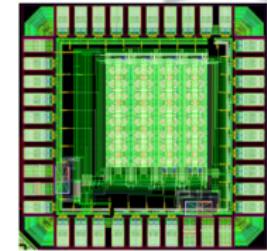
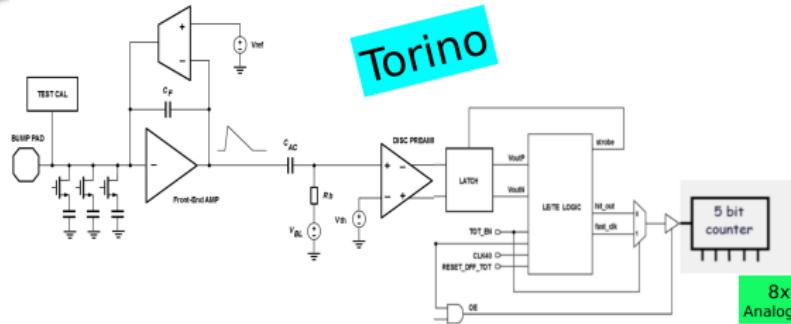


- Single ampli stage for minimum power dissipation (~5 uW)
- Krummenacher feedback to comply with the expected large increase in the detector leakage current (up to ~10 nA)
- 30000 electron maximum input charge expected, ~450 mV preampli output dynamic range
- Selectable gain, recovery current and detector emulating capacitance
- 40 MHz clock, 5 bit dual edge counter, 400 ns maximum ToT

Synchronous AFE



Synchronous Analog FE



8x8 pixel matrix submitted and tested
Analog readout of CSA and Discriminator (via buffers)

• PREAMPLIFIER

- One stage CSA with Krummenacher feedback

• Synchronous DISCRIMINATOR

- (AC coupled to CSA)
- off-set compensated diff.amplif. + latch;
- FAST Time-over-Threshold
 - Local oscillator strobing Latch (to 800MHz)

• Calibration circuit

- digital signal + DC calibration leve

Performance SUMMARY

- Compact: ~25um x 40 um
- Low power: < 5.5 uW (with ToT logic)
- Low noise: ENC=100e @ $C_{det}=100\text{ fF}$
- Leakage compensation: up to 50nA/pixel
- Fast Charge measurement:
 - 10 ke- in : 90 / 180 / 360 ns (Fast/Medium/Low recovery current)
 - up to 7-8bit (125-250e/ADC) - no ext clock
- NO Threshold-Trimming:
 - autozeroing made by hardware

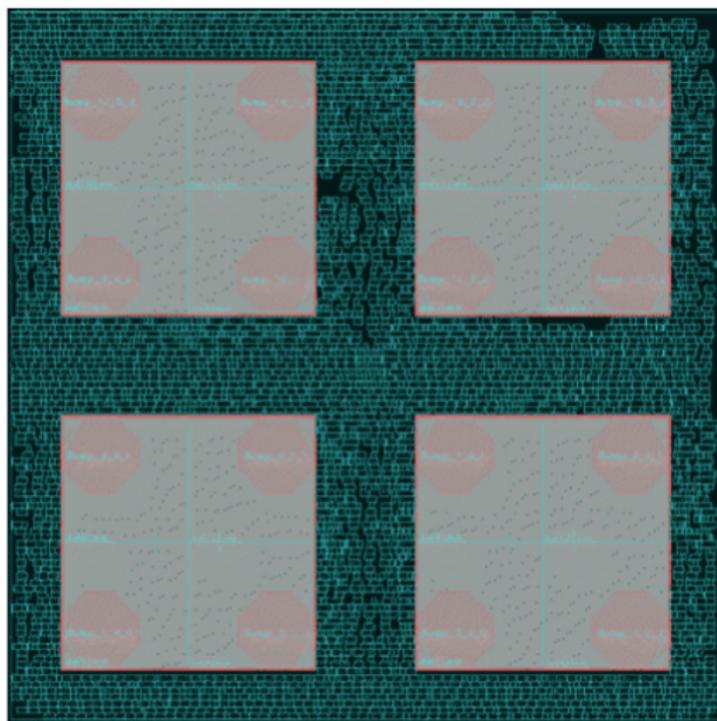
CHIPIX65 Demonstrator: Motivation (1)

- design a small yet fairly complex pixel array demonstrator in 65nm CMOS technology (intermediate step before full-scale RD53 prototype)
 - **64×64** pixels with **50um×50um** pixel size
 - independent development from FE65_P2
- integration of **two different flavours of analogue front-end** into the same digital readout/configuration architecture
 - asynchronous front-end chain (Pavia)
 - synchronous design (Torino)
- design and implementation of a **realistic and new region-based digital architecture**
 - usage of the **RD53 SystemVerilog/UVM verification environment** from the beginning
 - digital architecture studies performed with hits and trigger patterns provided by the verification environment
 - baseline choice of a **4×4 pixel-region**

CHIPIX65 Demonstrator: Motivation (2)

- **no ambition** to extend the exercise to complex digital readout/slow control
 - SPI-based chip configuration
 - simple column arbitering with RAM-based FIFO derandomizer and serializer
- integration of available **silicon-proved RD53 IP blocks**
 - biasing DAC and monitoring ADC (Bari), bandgap (Bergamo/Pavia)
 - sLVDS TX/RX (Bergamo/Pavia), serializer (Pisa)
 - others if available and successfully tested
- usage of the **modified CERN I/O library**
- core design-team based on INFN/CHIPIX65 groups
 - gain expertise and promote among INFN units the **digital-on-top (DoT) design methodology**
 - **ClioSoft-based** distributed design environment
 - periodic and detailed design reviews among designers
- **Multi-Project Wafer (MPW) run** submission planned for **Q1/2016**

CHIPIX65 Demonstrator: 4 x 4 pixel array



- Exercise with 'brute-force':
 - with 20us the digital area is very full (>80%)
- With second iteration (signal-only) promising early results
 - area@ 60%, low power (<4uW/px)
 - **working on it**

RD53A Demonstrator

- **2016 : RD53 Design of RD53A prototype**
 - 2-3 cm² prototype
 - Joined effort of the **whole RD53 collaboration**
 - Now definition / discussions o:
 - Technical Specs, Funding,
 - Milestone, Design team organization
 - submission end-2016
 - THIS WILL BE THE OUTPUT of RD53 Collaboration, closing the major part of R&D, communities will concentrate more into the chip for the experiments then.

• CHIPIX65 contributions

- Provide Analog Front End(s)
- Provide IP-blocks
- Digital architectures (shared work)
- CHIP integration (shared work)
- IP-block whould be in a stable 'final' version by middle/end of 2016
- Finance contribution:
 - about 1/5 of cost
 - cost ~ 500ke- 600ke

CHIPIX65 providing ~5 FTE
out of 10 (50%) - covering all
aspects

Contributo CHIPIX65

PV/BG: Gaioni, De Canio; TO: Monteil, Pacher, Paternò;
PG: Marconi; PI: Beccherle



CHIPIX65 activities

...at a glance

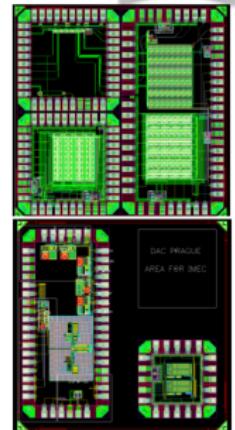


Radiation characterisation

- x-ray machine at LNL / Pd-INFN
 - Total Ionising Dose (TID)
 - 1 GRad in ~ 2 weeks
- Low-p at CN accelerator LNL
 - TID and Total Displacement damage
- TANDEM / SIRAD
 - Single Event Effects - with Heavy Ion
- Studies on n-MOS, p-MOS
- Irradiation of IP-block, Noise-measurements vs Irradiation

Design in 65nm

- 6 silicon dies 2x2mm² submitted
- CHIPIX65 IP-blocks
 - DAC-curr, ADC, SRAM, SER/DES, sLVDS(TX/RX)
 - BandGap, D2RA digital cells
 - JTAG
- CHIPIX65 Analog Very Front End
 - Synchronous chain
 - Asynchronous chain
- Integration of other RD53 IPs
 - DAC-volt (Prague)
 - SER (Bonn), BandGap (CPPM, CERN)



Digital Electronics:

- Simulation Framework
 - System-Verilog-UVM (VEPIX53)
- Digital Architecture Studies
- Input protocols definition
 - fast/efficient/continuos (while readout)
 - SEE robust

